eGaN® FET DATASHEET EPC2212

EPC2212 - Automotive 100 V (D-S) Enhancement **Mode Power Transistor**

V_{DS}, 100 V $R_{DS(on)}$, 13.5 m Ω I_D, 18 A **AEC-Q101**









Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)'}$ while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

	Maximum Ratings				
	PARAMETER	VALUE	UNIT		
V_{DS}	Drain-to-Source Voltage (Continuous)	100	V		
	Continuous (T _A = 25°C)	18	Δ.		
I _D	Pulsed (25°C, T _{PULSE} = 300 μs)	75	Α		
V	Gate-to-Source Voltage	6	V		
V _{GS}	Gate-to-Source Voltage	-4	V		
T	Operating Temperature	-40 to 150	°C		
T _{STG}	Storage Temperature	-40 to 150			

Thermal Characteristics				
	PARAMETER	TYP	UNIT	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	2		
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	4	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	69		

Note $1: R_{\theta,JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. $See \ https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf \ \ for \ details.$

	Static Characteristics ($T_J = 25^{\circ}$ C unless otherwise stated)					
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	100			٧
I _{DSS}	Drain-Source Leakage	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$		10	250	μΑ
	Gate-to-Source Forward Leakage	$V_{GS} = 6 \text{ V}, T_J = 25^{\circ}\text{C}$		0.005	1.8	m A
I _{GSS}	Gate-to-Source Forward Leakage#	$V_{GS} = 6 \text{ V}, T_J = 125^{\circ}\text{C}$		0.015	3	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		10	250	μΑ
V _{GS(TH)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 3 \text{ mA}$	0.7	1	2.5	٧
R _{DS(on)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 11 \text{ A}$		10	13.5	mΩ
V _{SD}	Source-Drain Forward Voltage#	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$		1.5		٧

All measurements were done with substrate connected to source. # Defined by design. Not subject to production test.



Die size: 2.1 x 1.6 mm

EPC2212 eGaN® FETs are supplied only in passivated die form with solder bars.

Applications

- · Lidar/Pulsed Power Applications
- High Power Density DC-DC Converters
- · Class-D Audio
- · High Intensity Headlamps

Benefits

- Ultra High Efficiency
- Ultra Low R_{DS(on)}
- Ultra Low Q_G
- Ultra Small Footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



https://l.ead.me/EPC2212

eGaN® FET DATASHEET EPC2212

Dynamic Characteristics [#] (T _J = 25°C unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance			339	407	
C_{RSS}	Reverse Transfer Capacitance	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}$		3		
Coss	Output Capacitance			238	357	рF
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 2)	V 040 50 V V 0 V		292		
C _{OSS(TR)}	Effective Output Capacitance, Time Related (Note 3)	$V_{DS} = 0 \text{ to } 50 \text{ V}, V_{GS} = 0 \text{ V}$		359		
R_{G}	Gate Resistance			0.4		Ω
Q _G	Total Gate Charge	$V_{DS} = 50 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 11 \text{ A}$		3.2	4	
Q_{GS}	Gate-to-Source Charge			0.9		
Q_{GD}	Gate-to-Drain Charge	$V_{DS} = 50 \text{ V, } I_D = 11 \text{ A}$		0.6		
Q _{G(TH)}	Gate Charge at Threshold			0.55		nC
Qoss	Output Charge	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}$		18	27	
Q _{RR}	Source-Drain Recovery Charge			0		

 $[\]ensuremath{\text{\#}}$ Defined by design. Not subject to production test.

Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 1: Typical Output Characteristics at 25°C

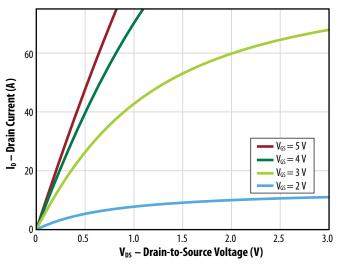


Figure 2: Typical Transfer Characteristics

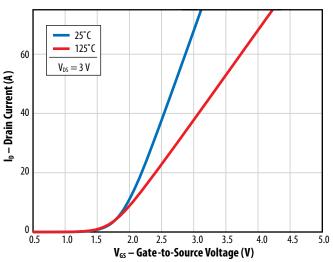


Figure 3: R_{DS(on)} vs. V_{GS} for Various Drain Currents

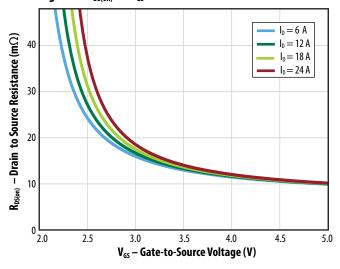
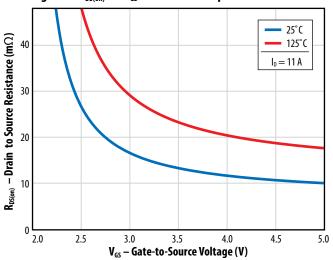


Figure 4: R_{DS(on)} vs. V_{GS} for Various Temperatures



All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

eGaN® FET DATASHEET **EPC2212**



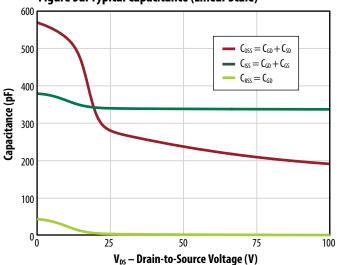


Figure 5b: Typical Capacitance (Log Scale)

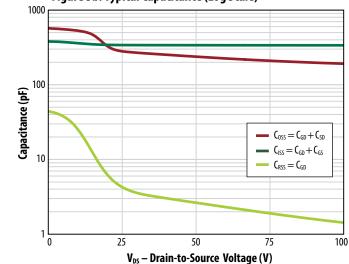


Figure 6: Typical Output Charge and Coss Stored Energy

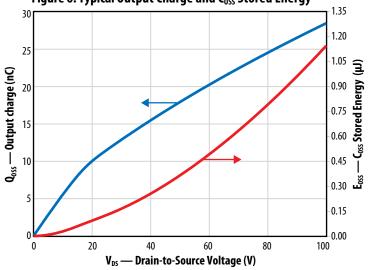


Figure 7: Typical Gate Charge

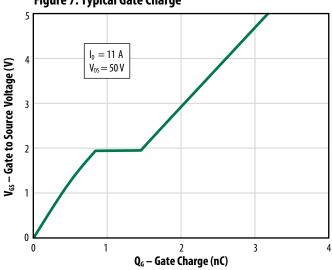
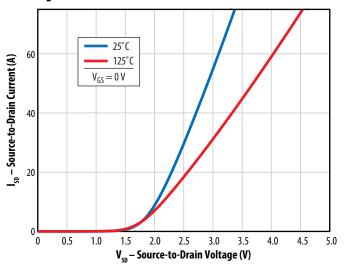


Figure 9: Normalized On-State Resistance vs. Temperature

Figure 8: Reverse Drain-Source Characteristics



Normalized On-State Resistance R_{DS(on)}

 $I_{D} = 11 \text{ A}$

 $V_{GS} = 5 \text{ V}$

2.2

0.8 0 25 50 75 100 125 150

T₁ – Junction Temperature (°C)

Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

eGaN® FET DATASHEET EPC2212

Figure 10: Normalized Threshold Voltage vs. Temperature

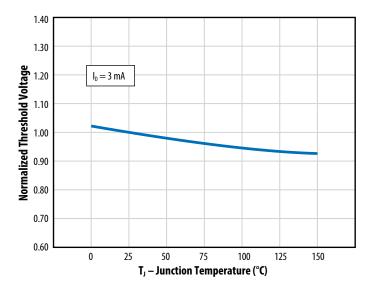


Figure 11: Transient Thermal Response Curves

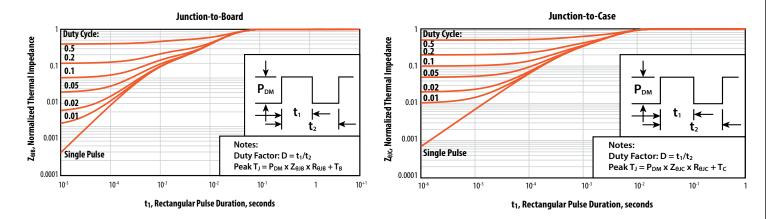
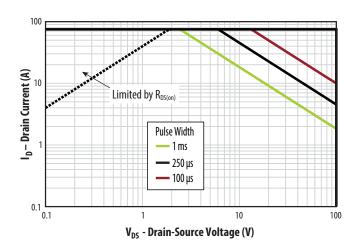
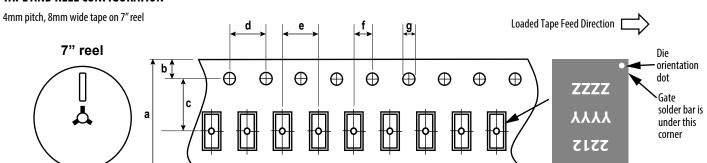


Figure 12: Safe Operating Area



EPC2212 eGaN® FET DATASHEET

TAPE AND REEL CONFIGURATION



1.60

1.50

	Dimension (mm)		
EPC2212 (Note 1)	Target	MIN	MAX
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (Note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
е	4.00	3.90	4.10
f (Note 2)	2.00	1.95	2.05

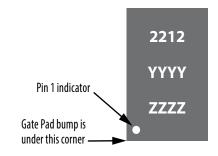
1.50

Die is placed into pocket solder bar side down (face side down)

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

DIE MARKINGS

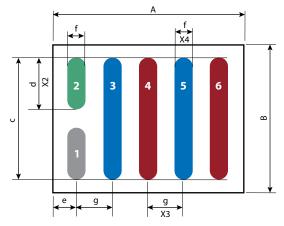


Dovit		Laser Markings	
Part Number	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2212	2212	YYYY	7777

eGaN® FET DATASHEET EPC2212

DIE OUTLINE

Solder Bar View



Pad no. 1 is Gate;

DIM

A

В

d

e

g

MIN

2076

1602

1379

577

235

195

400

Pads no. 3, 5 are Drain;

Pads no. 4, 6 are Source;

Pad no. 2 is Substrate.*

*Substrate pin should be connected to Source

MICROMETERS

Nominal

2106

1632

1382

580

250

200

400

MAX

2136

1662

1385

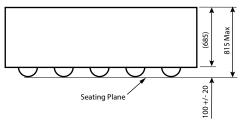
583

265

205

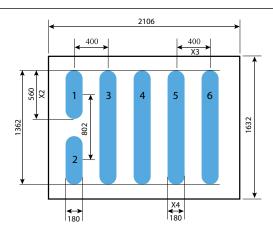
400

Side View



RECOMMENDED LAND PATTERN

(units in μ m)



The land pattern is solder mask defined.

Pad no. 1 is Gate;

Pads no. 3, 5 are Drain;

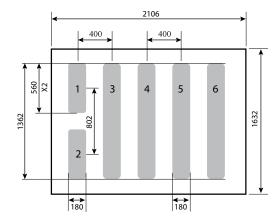
Pads no. 4, 6 are Source;

Pad no. 2 is Substrate. *

*Substrate pin should be connected to Source

RECOMMENDED STENCIL DRAWING

(measurements in μ m)



Recommended stencil should be 4mil (100 μ m) thick, must be laser cut , opening per drawing. The corner has a radius of R60

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others.

 $eGaN^{\circ}$ is a registered trademark of Efficient Power Conversion Corporation.

EPC Patent Listing: epc-co.com/epc/AboutEPC/Patents.aspx

Information subject to change without notice. Revised February, 2023